Notice of References Cited Application/Control No. 10/651,663 Examiner Yuwen Pan Applicant(s)/Patent Under Reexamination XIE, FEI Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,044,341	03-2000	Takahashi, Hidetaka	704/226
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					-
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		. Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	x	

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